

MOS FIELD EFFECT TRANSISTOR

2SK3435

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

The 2SK3435 is N-channel MOS Field Effect Transistor designed for high current switching applications.

FEATURES

• Super low on-state resistance

RDS(on)1 = 14 m Ω MAX. (VGS = 10 V, ID = 40 A) RDS(on)2 = 22 m Ω MAX. (VGS = 4.0 V, ID = 40 A)

- Low Ciss: Ciss = 3200 pF TYP.
- Built-in gate protection diode

ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3435	TO-220AB
2SK3435-S	TO-262
2SK3435-ZJ	TO-263
2SK3435-Z	TO-220SMD Note

Note TO-220SMD package is produced only in Japan.

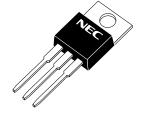
(TO-220AB)

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vss = 0 V)	VDSS	60	V
Gate to Source Voltage (VDS = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	I _{D(DC)}	±80	Α
Drain Current (pulse) Note1	D(pulse)	±160	Α
Total Power Dissipation (Tc = 25°C)	Рт	84	W
Total Power Dissipation (T _A = 25°C)	Рт	1.5	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C
Single Avalanche Current Note2	las	31	Α
Single Avalanche Energy Note2	Eas	96	mJ

Notes 1. PW \leq 10 μ s, Duty cycle \leq 1%

2. Starting T_{ch} = 25°C, V_{DD} = 30 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V



(TO-262)



(TO-220SMD)



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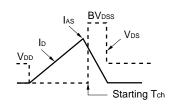


ELECTRICAL CHARACTERISTICS (TA = 25°C)

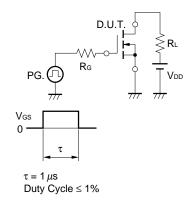
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero gate Voltage Drain Current	IDSS	V _{DS} = 60 V, V _{GS} = 0 V			10	μΑ
Gate Leakage Current	lgss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	٧
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 40 A	21	43		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 40 A		11	14	mΩ
	R _{DS(on)2}	Vgs = 4.0 V, ID = 40 A		16	22	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		3200		pF
Output Capacitance	Coss	V _G S = 0 V		520		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		260		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 30 V, I _D = 40 A		80		ns
Rise Time	tr	V _{GS} = 10 V		1200		ns
Turn-off Delay Time	td(off)	$R_G = 10 \Omega$		200		ns
Fall Time	tf			350		ns
Total Gate Charge	Q _G	V _{DD} = 48 V		60		nC
Gate to Source Charge	Qgs	V _{GS} = 10 V		10		nC
Gate to Drain Charge	Q _{GD}	ID = 80 A		16		nC
Body Diode Forward Voltage	V _F (S-D)	IF = 80 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	IF = 80 A, VGS = 0 V		46		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		66		nC

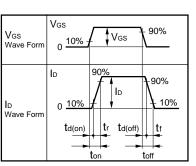
TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c|c} D.U.T. \\ \hline R_G = 25 \ \Omega \\ \hline PG. \\ \hline \\ V_{GS} = 20 \rightarrow 0 \ V \end{array}$

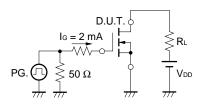


TEST CIRCUIT 2 SWITCHING TIME



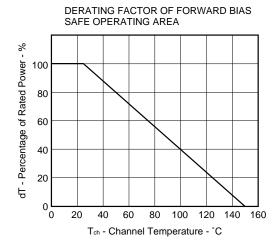


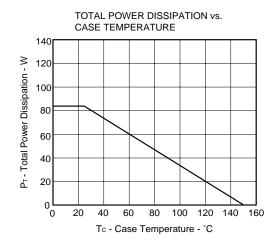
TEST CIRCUIT 3 GATE CHARGE



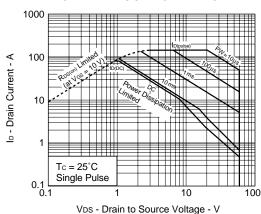


TYPICAL CHARACTERISTICS (TA = 25°C)

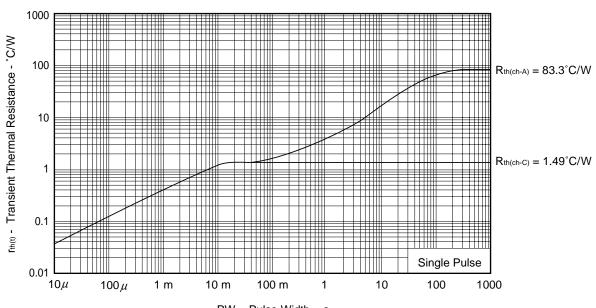




FORWARD BIAS SAFE OPERATING AREA

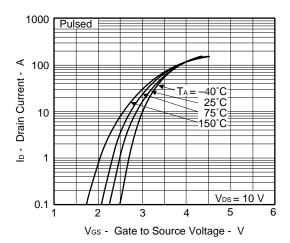


TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

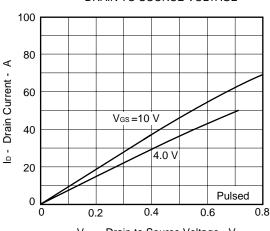


PW - Pulse Width - s

FORWARD TRANSFER CHARACTERISTICS

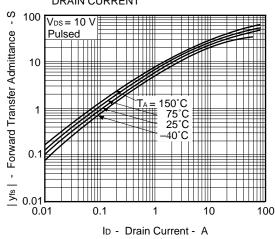


DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE

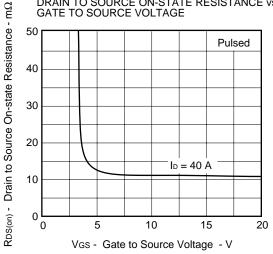


V_{DS} - Drain to Source Voltage - V

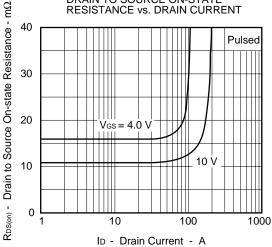
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



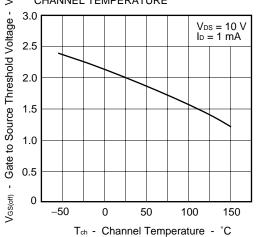
DRAIN TO SOURCE ON-STATE RESISTANCE vs GATE TO SOURCE VOLTAGE



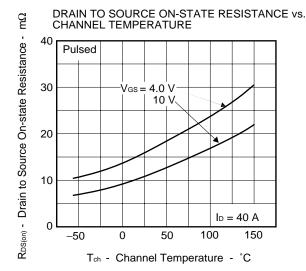




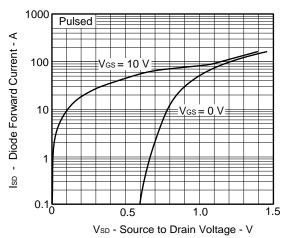
GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

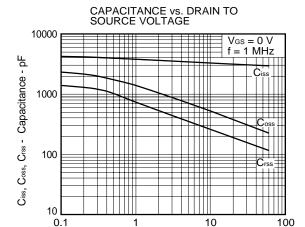




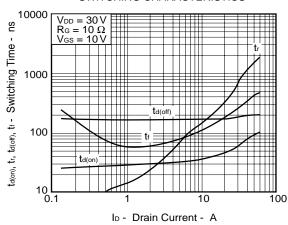


SOURCE TO DRAIN DIODE FORWARD VOLTAGE



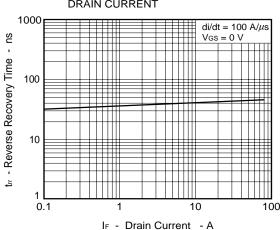


SWITCHING CHARACTERISTICS

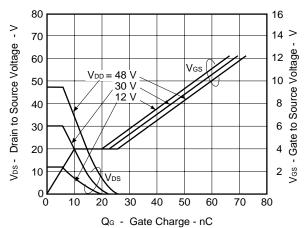


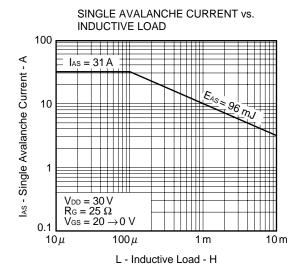


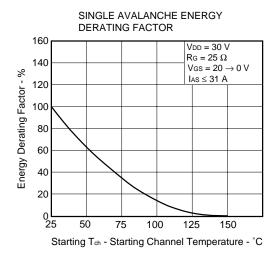
V_{DS} - Drain to Source Voltage - V



DYNAMIC INPUT/OUTPUT CHARACTERISTICS



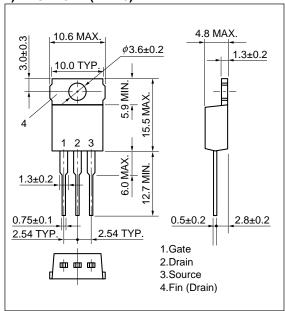




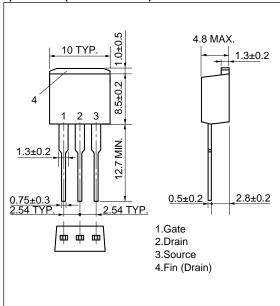


★ PACKAGE DRAWINGS (Unit: mm)

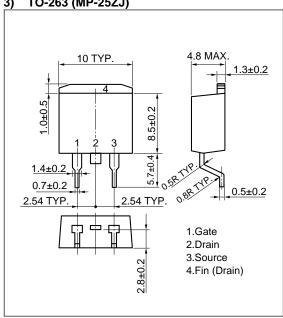
1) TO-220AB (MP-25)



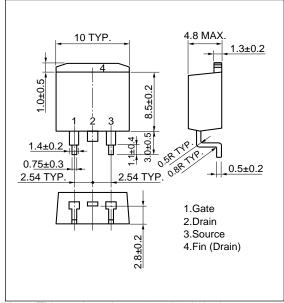
2) TO-262 (MP-25 Fin Cut)



3) TO-263 (MP-25ZJ)

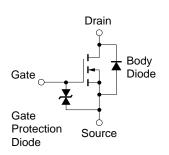


4) TO-220SMD (MP-25Z)^{Note}



Note This package is produced only in Japan.

EQUIVALENT CIRCUIT



Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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